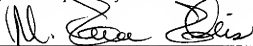


PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

*I hereby certify that this correspondence is being electronically filed with the United States Patent and Trademark Office on July 24, 2007 at or before 11:59 pm Pacific Time under the Rules of 37 CFR § 1.8.*

  
M. Ena Ellis

Appl No. : 10/674,654 Confirmation No. 4784  
Applicant : Akio Ishikawa  
Filed : September 29, 2003  
Title : IMAGE DEFECT INSPECTION METHOD, IMAGE DEFECT  
INSPECTION APPARATUS AND APPEARANCE INSPECTION  
APPARATUS  
TC/A.U. : 2624  
Examiner : John B. Strege  
Docket No. : 51272/A400  
Customer No. : 23363

RESPONSE

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Post Office Box 7068  
Pasadena, CA 91109-7068  
July 24, 2007

Commissioner:

In response to the Office action of April 24, 2007, please consider the remarks as follows:

**Listing of the claims** begins on page 2 of this paper.

**Remarks/Arguments** begin on page 13 of this paper.